

	Type	Hits	Search Text	DBs	Time Stamp
1	IS&R	2929	(257/48,723,724).CCLS.	USPAT	2006/04/14 11:13
2	IS&R	2207	(438/11,14,15,18).CCLS.	USPAT	2006/04/14 11:15
3	IS&R	2185	(257/48,723,724).CCLS.	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	2006/04/14 11:19
4	IS&R	834	(438/11,14,15,18).CCLS.	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	2006/04/14 11:20
5	BRS	291	S30 and (chip die) and (transistor gate FET)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	2006/04/14 11:21
6	BRS	174	S31 and (chip die) and (transistor gate FET)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	2006/04/14 11:21
7	BRS	6	(chip die) and (input) and (output) and (transistor gate selector FET) and ((nominal average) near2 resistance) and (compensation near2 circuit) and (check checking test testing)	USPAT	2006/04/14 14:46
8	BRS	3	(chip die) and (input) and (output) and (transistor gate selector FET) and ((nominal average) near2 resistance) and (compensation near2 circuit) and (check checking test testing)	US-PGPUB; USOCR; EPO; JPO; DERWENT; IBM_TDB	2006/04/14 15:00
9	BRS	0	((chip die) and (input) and (output) and (transistor gate selector FET) and ((nominal average) near2 resistance) and (compensation near2 circuit) and (check checking test testing)).clm.	US-PGPUB	2006/04/14 15:00

	Type	Hits	Search Text	DBs	Time Stamp
10	BRS	1	((chip die) and (input) and (output) and (transistor gate selector FET) and (resistance) and (compensation near2 circuit) and (check checking test testing)).clm.	US-PGPUB	2006/04/14 15:03